

<b>Notice of References Cited</b>	Application/Control No. 10/736,833		Applicant(s)/Patent Under Reexamination LEE, EUN-SOO	
	Examiner Jermele M. Hollington.		Art Unit 2829	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,307,011 A	04-1994	Tani, Mitsuaki	324/158.1
*	B	US-5,313,156 A	05-1994	Klug et al.	324/158.1
*	C	US-5,319,353 A	06-1994	Ohnishi et al.	340/525
*	D	US-5,742,168 A	04-1998	Kiyokawa et al.	324/754
*	E	US-5,788,084 A	08-1998	Onishi et al.	324/158.1
*	F	US-5,909,657 A	06-1999	Onishi et al.	702/108
*	G	US-6,198,273 B1	03-2001	Onishi et al.	324/754
*	H	US-6,384,593 B1	05-2002	Kobayashi et al.	324/765
*	I	US-6,515,470 B2	02-2003	Suzuki et al.	324/754
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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